Claims 1-23 (canceled)

- 24. (currently amended) A semiconductor package comprising:
- a substrate comprising a first surface [,] and a second surface;
- , a plurality of conductors on the first surface, and a bonding opening from the first surface to the second surface;
- a semiconductor die having a first outline and a face on the bonding opening bonded directly to the second surface;
 - a first mask on the first surface;
- a second mask covering the second surface except in a die attach area defined by an opening through the second mask having a second outline corresponding to the first outline;
- an adhesive layer between the face and the die attach area bonding the die <u>directly</u> to the <u>substrate</u> <u>second</u> <u>surface</u>; <u>and</u>
- a plurality of wires in the bonding opening wire bonded to the die and in electrical communication with the conductors; and
- an encapsulating resin on the die and on the second mask.
- 25. (currently amended) The package of claim 24 wherein the <u>second outline</u> is only slightly larger than the <u>first outline</u>.

encapsulating resin comprises epoxy.

26. (currently amended) The package of claim 25 wherein the adhesive layer comprises a filled adhesive

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epoxy, acrylic or polyimide material configured to transfer heat directly from the face to the second surface.

- 27. (currently amended) A semiconductor package comprising:
- a substrate comprising a first surface [,] <u>and</u> a second surface;
- , a plurality of conductors on the first surface, a plurality of wire bonding pads on the first surface in electrical communication with the conductors, and a bonding opening from the first surface to the second surface;
- a semiconductor die having a first outline and a face on the bonding opening bonded directly to the second surface;
 - a first mask on the first surface;
- a second mask on the second surface comprising a second opening having a second outline corresponding to the first outline defining an open die attach area on the second surface;
- a filled adhesive layer between the face and the die attach area bonding the die to the substrate and configured to transfer heat directly from the face to the substrate; and
- a plurality of wires in the bonding opening wire bonded to the die and to the wire bonding pads; and
- an encapsulating resin on the die and on the second mask.
- 28. (currently amended) The package of claim 27 wherein the filled adhesive layer comprises a material selected from the group consisting of epoxy, acrylic and polyimide.

further comprising a glob top in the bonding opening and on the first surface at least partially encapsulating the wires.

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29. (currently amended) The package of claim 27 wherein the <u>second outline is only slightly larger than the</u> first outline.

first mask and the second mask comprise a photoimageable material.

- 30. (currently amended) A semiconductor package comprising:
- a substrate having a first surface, a second surface and a bonding opening there through;
- a plurality of conductors on the first surface having a plurality of wire bonding pads;
- a first mask on the first surface at least partially covering the conductors;
- a second mask on the second surface except in a die attach area defined by an opening in the second mask;
- a semiconductor die on the die attach area having a face aligned with the bonding opening attached <u>directly</u> to the second surface;
- a filled adhesive layer attaching the face <u>directly</u> to the die attach area and configured to transfer heat directly from the face to the substrate;
- a plurality of wires in the bonding opening bonded to the die and to the wire bonding pads; and
- an encapsulating resin on the second mask encapsulating the die.
- 31. (currently amended) The package of claim 30 wherein the <u>die attach area has an outline only slightly larger than that of the die.</u>

encapsulating resin comprises epoxy.

32. (currently amended) The package of claim 30 wherein the substrate comprises an organic polymer.

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further comprising a polymer in the bonding opening and on the first surface at least partially encapsulating the wires.

- 33. (currently amended) The package of claim 30 wherein the adhesive layer comprises a filled material selected from the group consisting of epoxy, acrylic and polyimide.
- 34. (currently amended) A semiconductor package comprising:
- a substrate comprising a first surface, an opposing second surface and a wire bonding opening from the first surface to the second surface;
- a plurality of conductors on the first surface comprising wire bonding pads;
 - a first mask on the first surface;
- a semiconductor die aligned with the wire bonding opening and bonded face down <u>directly</u> to the second surface, the die having a first outline;
- a second mask substantially covering the second surface and including an opening there through having a second outline corresponding to but only slightly larger than the first outline defining a die attach area on the second surface;

an adhesive layer between the die and the die attach area bonding the die <u>directly</u> to the <u>substrate</u> <u>second</u> <u>surface</u>;

- a plurality of wires in the wire bonding opening bonded to the die and to the wire bonding pads; and
- an encapsulating resin on the second mask encapsulating the die.
- 35. (currently amended) The package of claim 34 wherein the second outline is only slightly larger than the first outline.

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further comprising a glob top in the wire bonding opening at least partially encapsulating the wires.

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36. (currently amended) The package of claim 34 wherein the adhesive layer comprises a filled epoxy adhesive configured to transfer heat directly from the face to the substrate.